Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/604,796	CHANG ET AL.
Examiner	Art Unit
Hashem Farrokh	2187

SEARCHED				
Class	Subclass	Date	Examiner	
711	1-3,101- 105,111- 115,167	7/30/2005	HF	
712	1,38,43	7/30/2005	HF	
v.s				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
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SEARCH (INCLUDING SEAF		<u>()</u>
	DATE	EXMR
PALM Inventor Search	7/28/2005	HF
Brian Peugh	8/1/2005	HF
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